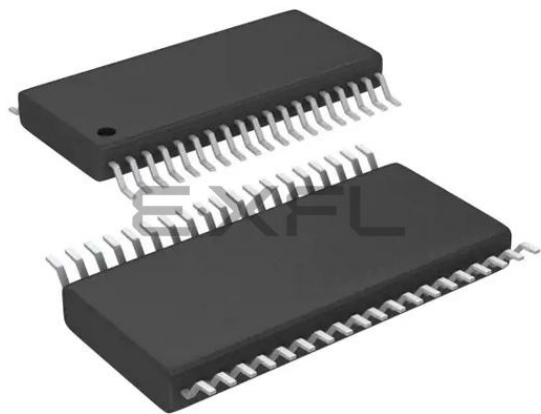




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Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	26
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1302t038x0128aaxuma1

Summary of Features
Table 1 Synopsis of XMC1300 Device Types (cont'd)

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1302-T016X0008	PG-TSSOP-16-8	8	16
XMC1302-T016X0016	PG-TSSOP-16-8	16	16
XMC1302-T016X0032	PG-TSSOP-16-8	32	16
XMC1301-T038F0008	PG-TSSOP-38-9	8	16
XMC1301-T038F0016	PG-TSSOP-38-9	16	16
XMC1301-T038F0032	PG-TSSOP-38-9	32	16
XMC1302-T038X0016	PG-TSSOP-38-9	16	16
XMC1302-T038X0032	PG-TSSOP-38-9	32	16
XMC1302-T038X0064	PG-TSSOP-38-9	64	16
XMC1302-T038X0128	PG-TSSOP-38-9	128	16
XMC1302-T038X0200	PG-TSSOP-38-9	200	16
XMC1301-Q024F0008	PG-VQFN-24-19	8	16
XMC1301-Q024F0016	PG-VQFN-24-19	16	16
XMC1302-Q024F0016	PG-VQFN-24-19	16	16
XMC1302-Q024F0032	PG-VQFN-24-19	32	16
XMC1302-Q024F0064	PG-VQFN-24-19	64	16
XMC1302-Q024X0016	PG-VQFN-24-19	16	16
XMC1302-Q024X0032	PG-VQFN-24-19	32	16
XMC1302-Q024X0064	PG-VQFN-24-19	64	16
XMC1301-Q040F0008	PG-VQFN-40-13	8	16
XMC1301-Q040F0016	PG-VQFN-40-13	16	16
XMC1301-Q040F0032	PG-VQFN-40-13	32	16
XMC1302-Q040X0016	PG-VQFN-40-13	16	16
XMC1302-Q040X0032	PG-VQFN-40-13	32	16
XMC1302-Q040X0064	PG-VQFN-40-13	64	16
XMC1302-Q040X0128	PG-VQFN-40-13	128	16

1.3 Device Type Features

The following table lists the available features per device type.

Summary of Features
Table 4 XMC1300 Chip Identification Number (cont'd)

Derivative	Value	Marking
XMC1302-Q024F0016	00013062 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-Q024F0032	00013062 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q024F0064	00013062 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1302-Q024X0016	00013063 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-Q024X0032	00013063 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q024X0064	00013063 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1301-Q040F0008	00013042 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-Q040F0016	00013042 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1301-Q040F0032	00013042 01CF00FF 00001FF7 0000100F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q040X0016	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-Q040X0032	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q040X0064	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1302-Q040X0128	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00021000 101ED083 _H	AA

2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

2.1 Logic Symbols

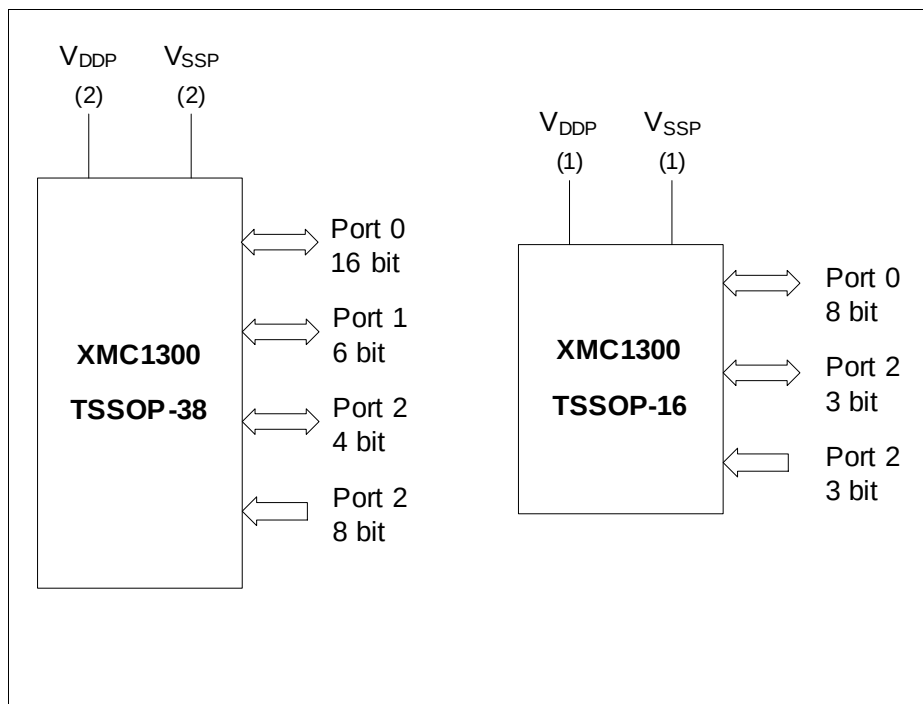


Figure 2 XMC1300 Logic Symbol for TSSOP-38 and TSSOP-16

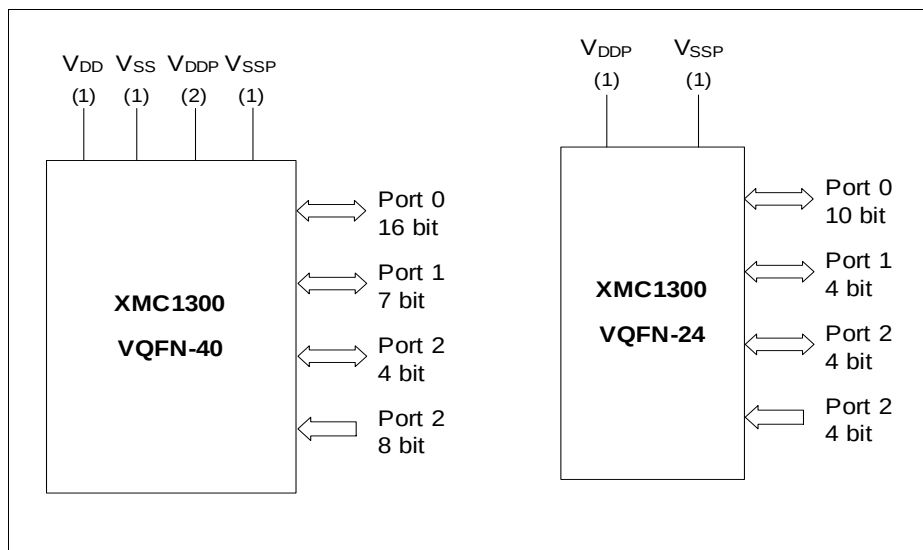


Figure 3 XMC1300 Logic Symbol for VQFN-24 and VQFN-40

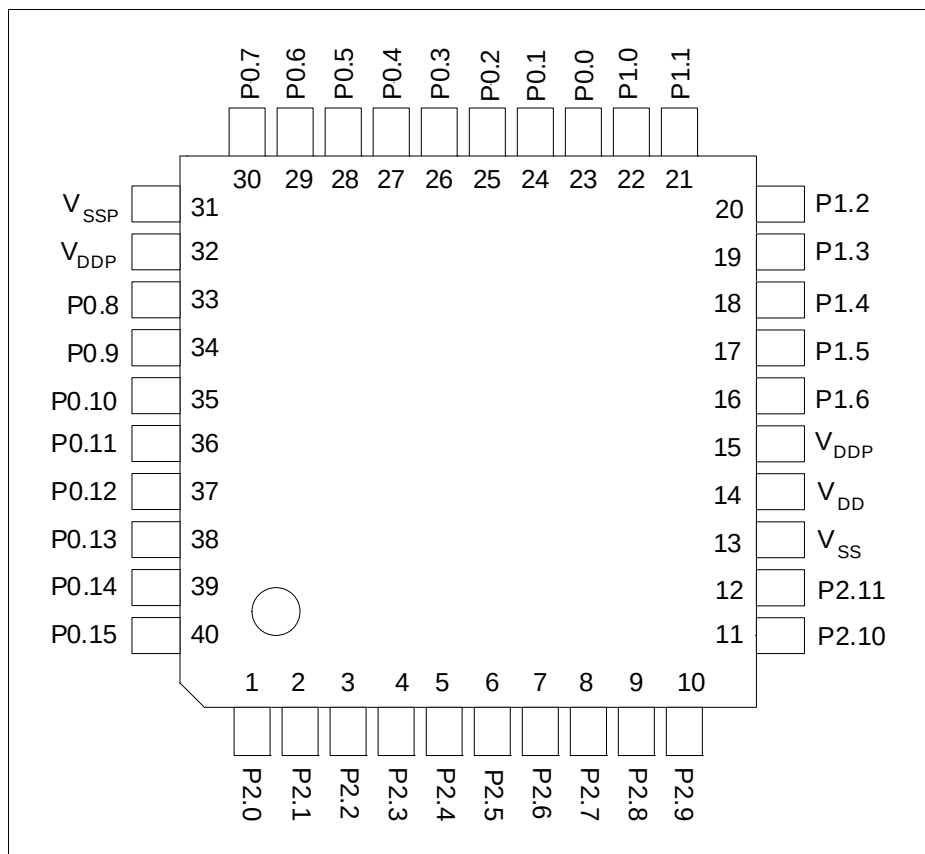


Figure 7 XMC1300 PG-VQFN-40 Pin Configuration (top view)

2.2.1 Package Pin Summary

The following general building block is used to describe each pin:

Table 5 Package Pin Mapping Description

Function	Package A	Package B	...	Pad Type
Px.y	N	N		Pad Class

The table is sorted by the "Function" column, starting with the regular Port pins (Px.y), followed by the supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The "Pad Type" indicates the employed pad type:

- STD_INOUT(standard bi-directional pads)
- STD_INOUT/AN (standard bi-directional pads with analog input)
- High Current (high current bi-directional pads)
- STD_IN/AN (standard input pads with analog input)
- Power (power supply)

Details about the pad properties are defined in the Electrical Parameters.

Table 6 Package Pin Mapping

Function	VQFN 40	TSSOP 38	VQFN 24	TSSOP 16	Pad Type	Notes
P0.0	23	17	15	7	STD_INOUT	
P0.1	24	18	-	-	STD_INOUT	
P0.2	25	19	-	-	STD_INOUT	
P0.3	26	20	-	-	STD_INOUT	
P0.4	27	21	-	-	STD_INOUT	
P0.5	28	22	16	8	STD_INOUT	
P0.6	29	23	17	9	STD_INOUT	
P0.7	30	24	18	10	STD_INOUT	
P0.8	33	27	19	11	STD_INOUT	
P0.9	34	28	20	12	STD_INOUT	
P0.10	35	29	-	-	STD_INOUT	
P0.11	36	30	-	-	STD_INOUT	
P0.12	37	31	21	-	STD_INOUT	

Table 8 Port I/O Functions (cont'd)

Function	Outputs									Inputs									
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	HWO0	HWO1	HWI0	HWI1	Input	Input	Input	Input	Input	Input	Input	Input
P1.6	VADC0.EMUX12	USIC0_CH1.DOUT0		USIC0_CH0.SCLKOUT	BCCU0.OUT2	USIC0_CH0.SELO2	USIC0_CH1.SELO3							USIC0_CH0.DX5F					
P2.0	ERU0.PDOUT3	CCU40.OUT0	ERU0.GOUT3		CCU80.OUT20	USIC0_CH0.DOUT0	USIC0_CH0.SCLKOUT						VADC0.G0CH5		ERU0.0B0	USIC0_CH0.DX0E	USIC0_CH0.DX1E	USIC0_CH1.DX2F	
P2.1	ERU0.PDOUT2	CCU40.OUT1	ERU0.GOUT2		CCU80.OUT21	USIC0_CH0.DOUT0	USIC0_CH1.SCLKOUT					ACMP2.INP	VADC0.G0CH6		ERU0.1B0	USIC0_CH0.DX0F	USIC0_CH1.DX3A	USIC0_CH1.DX4A	
P2.2												ACMP2.INN	VADC0.G0CH7		ERU0.0B1	USIC0_CH0.DX3A	USIC0_CH0.DX4A	USIC0_CH1.DX5A	ORC0.AIN
P2.3													VADC0.G1CH5		ERU0.1B1	USIC0_CH0.DX5B	USIC0_CH1.DX3C	USIC0_CH1.DX4C	ORC1.AIN
P2.4													VADC0.G1CH6		ERU0.0A1	USIC0_CH0.DX3B	USIC0_CH0.DX4B	USIC0_CH1.DX5B	ORC2.AIN
P2.5													VADC0.G1CH7		ERU0.1A1	USIC0_CH0.DX5D	USIC0_CH1.DX3E	USIC0_CH1.DX4E	ORC3.AIN
P2.6												ACMP1.INN	VADC0.G0CH0		ERU0.2A1	USIC0_CH0.DX3E	USIC0_CH0.DX4E	USIC0_CH1.DX5D	ORC4.AIN
P2.7												ACMP1.INP	VADC0.G1CH1		ERU0.3A1	USIC0_CH0.DX5C	USIC0_CH1.DX3D	USIC0_CH1.DX4D	ORC5.AIN
P2.8												ACMP0.INN	VADC0.G0CH1	VADC0.G1CH0	ERU0.3B1	USIC0_CH0.DX3D	USIC0_CH0.DX4D	USIC0_CH1.DX5C	ORC6.AIN
P2.9												ACMP0.INP	VADC0.G0CH2	VADC0.G1CH4	ERU0.3B0	USIC0_CH0.DX5A	USIC0_CH1.DX3B	USIC0_CH1.DX4B	ORC7.AIN
P2.10	ERU0.PDOUT1	CCU40.OUT2	ERU0.GOUT1		CCU80.OUT30	ACMP0.OUT	USIC0_CH1.DOUT0						VADC0.G0CH3	VADC0.G1CH2	ERU0.2B0	USIC0_CH0.DX3C	USIC0_CH0.DX4C	USIC0_CH1.DX0F	
P2.11	ERU0.PDOUT0	CCU40.OUT3	ERU0.GOUT0		CCU80.OUT31	USIC0_CH1.SCLKOUT	USIC0_CH1.DOUT0					ACMP.REF	VADC0.G0CH4	VADC0.G1CH3	ERU0.2B1	USIC0_CH1.DX0E	USIC0_CH1.DX1E		

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 9 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Cond ition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_S	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on any pin with respect to V_{SSP}	V_{IN}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Voltage on any analog input pin with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	–
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute sum of all input currents during overload condition	$\Sigma I_{IN} $	SR	–	–	50	mA	–
Analog comparator input voltage	V_{CM}	SR	-0.3	–	$V_{DDP} + 0.3$	V	

Electrical Parameter
Table 12 ADC Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum sample rate in 8-bit mode ³⁾	f_{C8} CC	–	–	$f_{ADC} / 38.5$	–	1 sample pending
		–	–	$f_{ADC} / 54.5$	–	2 samples pending
DNL error	EA_{DNL} CC	–	±2.0	–	LSB 12	
INL error	EA_{INL} CC	–	±4.0	–	LSB 12	
Gain error with external reference	EA_{GAIN} CC	–	±0.5	–	%	SHSCFG.AREF = 00 _B (calibrated)
Gain error with internal reference	EA_{GAIN} CC	–	±3.6	–	%	SHSCFG.AREF = 1X _B (calibrated), -40°C - 105°C
		–	±2.0	–	%	SHSCFG.AREF = 1X _B (calibrated), 0°C - 85°C
Offset error	EA_{OFF} CC	–	±6.0	–	LSB 12	Calibrated

1) Not subject to production test, verified by design/characterization.

2) No pending samples assumed, excluding sampling time and calibration.

3) Includes synchronization and calibration (average of gain and offset calibration).

3.2.3 Out of Range Comparator (ORC) Characteristics

The Out-of-Range Comparator (ORC) triggers on analog input voltages (V_{AIN}) above the V_{DDP} on selected input pins (ORCx.AIN) and generates a service request trigger (ORCx.OUT).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 13 Out of Range Comparator (ORC) Characteristics (Operating Conditions apply; $V_{DDP} = 3.0\text{ V} - 5.5\text{ V}$; $C_L = 0.25\text{ pF}$)

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
DC Switching Level	V_{ODC}	CC	60	–	120	mV	$V_{AIN} \geq V_{DDP} + V_{ODC}$
Hysteresis	V_{OHYS}	CC	25	–	V_{ODC}	mV	
Always detected Overvoltage Pulse	t_{OPDD}	CC	103	–	–	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			88	–	–	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Never detected Overvoltage Pulse	t_{OPDN}	CC	–	–	21	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			–	–	11	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Detection Delay	t_{ODD}	CC	39	–	132	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			31	–	121	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Release Delay	t_{ORD}	CC	44	–	240	ns	$V_{AIN} \leq V_{DDP}$; $V_{DDP} = 5\text{ V}$
			57	–	340	ns	$V_{AIN} \leq V_{DDP}$; $V_{DDP} = 3.3\text{ V}$
Enable Delay	t_{OED}	CC	–	–	300	ns	ORCCTRL.ENORCx = 1

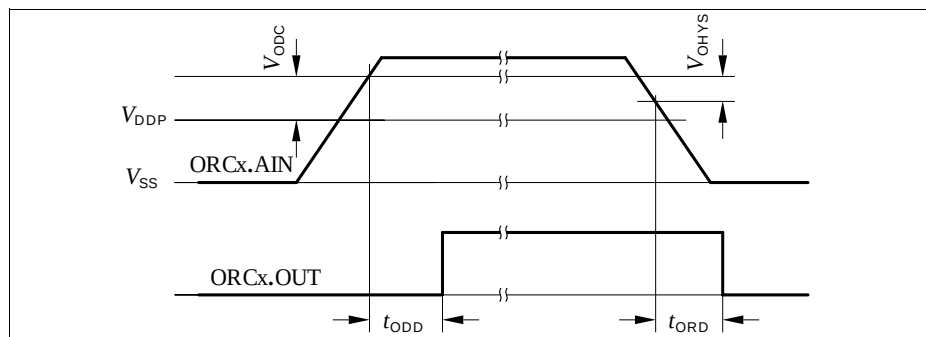


Figure 9 ORCx.OUT Trigger Generation

3.3.2 Output Rise/Fall Times

Table 19 provides the characteristics of the output rise/fall times in the XMC1300. **Figure 10** describes the rise time and fall time parameters.

Table 19 Output Rise/Fall Times Parameters (Operating Conditions apply)

Parameter	Symbol	Limit Values		Unit	Test Conditions
		Min.	Max.		
Rise/fall times on High Current Pad ¹⁾²⁾	$t_{\text{HCPR}}, t_{\text{HCPF}}$	—	9	ns	50 pF @ 5 V ³⁾
		—	12	ns	50 pF @ 3.3 V ⁴⁾
		—	25	ns	50 pF @ 1.8 V ⁵⁾
Rise/fall times on Standard Pad ¹⁾²⁾	$t_{\text{R}}, t_{\text{F}}$	—	12	ns	50 pF @ 5 V ⁶⁾
		—	15	ns	50 pF @ 3.3 V ⁷⁾
		—	31	ns	50 pF @ 1.8 V ⁸⁾

1) Rise/Fall time parameters are taken with 10% - 90% of supply.

2) Not all parameters are 100% tested, but are verified by design/characterisation and test correlation.

3) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.150 ns/pF at 5 V supply voltage.

4) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.205 ns/pF at 3.3 V supply voltage.

5) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.445 ns/pF at 1.8 V supply voltage.

6) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.225 ns/pF at 5 V supply voltage.

7) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.288 ns/pF at 3.3 V supply voltage.

8) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.588 ns/pF at 1.8 V supply voltage.

3.3.4 On-Chip Oscillator Characteristics

Table 21 provides the characteristics of the 64 MHz clock output from the digital controlled oscillator, DCO1 in XMC1300.

Table 21 64 MHz DCO1 Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Test Conditions
			Min.	Typ.	Max.		
Nominal frequency	f_{NOM}	CC	63.5	64	64.5	MHz	under nominal conditions ¹⁾ after trimming
Accuracy	Δf_{LT}	CC	-1.7	–	3.4	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature ($T_A = 0\text{ °C}$ to 85 °C) ²⁾
			-3.9	–	4.0	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature ($T_A = -40\text{ °C}$ to 105 °C) ²⁾
Accuracy with calibration based on temperature sensor	Δf_{LTT}	CC	-1.3	–	1.25	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature ($T_A = 0\text{ °C}$ to 105 °C) ²⁾
			-2.6	–	1.25	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature ($T_A = -40\text{ °C}$ to 105 °C) ²⁾

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and $T_A = +25\text{ °C}$.

2) Not subject to production test, verified by design/characterisation.

Electrical Parameter

Figure 14 shows the typical curves for the accuracy of DCO1, with and without calibration based on temperature sensor, respectively.

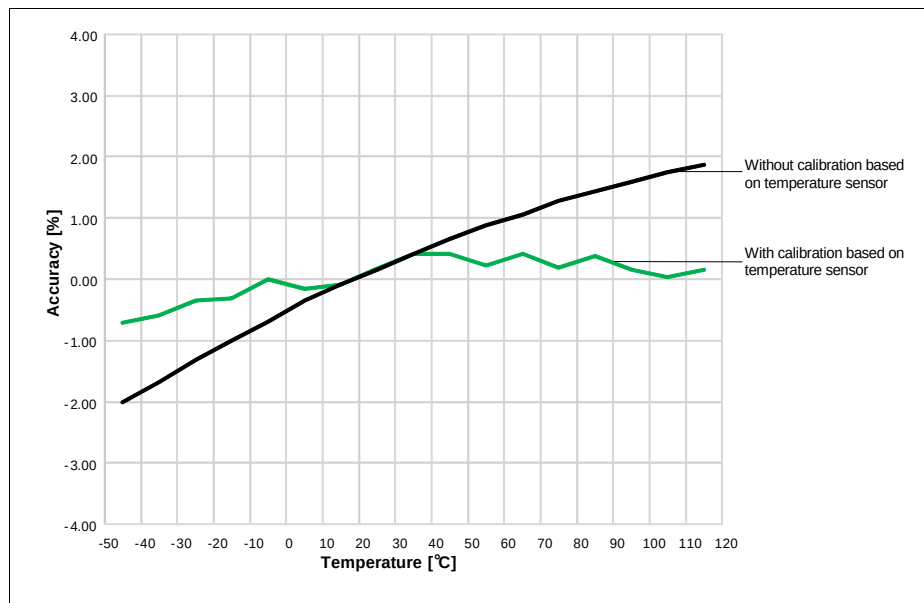


Figure 14 Typical DCO1 accuracy over temperature

Table 22 provides the characteristics of the 32 kHz clock output from digital controlled oscillators, DCO2 in XMC1300.

Table 22 32 kHz DCO2 Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Test Conditions
			Min.	Typ.	Max.		
Nominal frequency	f_{NOM}	CC	32.5	32.75	33	kHz	under nominal conditions ¹⁾ after trimming
Accuracy	Δf_{LT}	CC	-1.7	—	3.4	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (0 °C to 85 °C) ²⁾
			-3.9	—	4.0	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (-40 °C to 105 °C) ²⁾

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and $T_{\text{A}} = + 25\text{ °C}$.

2) Not subject to production test, verified by design/characterisation.

3.3.7 Peripheral Timings

Note: These parameters are not subject to production test, but verified by design and/or characterization.

3.3.7.1 Synchronous Serial Interface (USIC SSC) Timing

The following parameters are applicable for a USIC channel operated in SSC mode.

Note: Operating Conditions apply.

Table 25 USIC SSC Master Mode Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Slave select output SELO active to first SCLKOUT transmit edge	t_1 CC	80	–	–	ns	
Slave select output SELO inactive after last SCLKOUT receive edge	t_2 CC	0	–	–	ns	
Data output DOUT[3:0] valid time	t_3 CC	-10	–	10	ns	
Receive data input DX0/DX[5:3] setup time to SCLKOUT receive edge	t_4 SR	80	–	–	ns	
Data input DX0/DX[5:3] hold time from SCLKOUT receive edge	t_5 SR	0	–	–	ns	

Table 26 USIC SSC Slave Mode Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 setup to first clock input DX1 transmit edge ¹⁾	t_{10} SR	10	–	–	ns	
Select input DX2 hold after last clock input DX1 receive edge ¹⁾	t_{11} SR	10	–	–	ns	

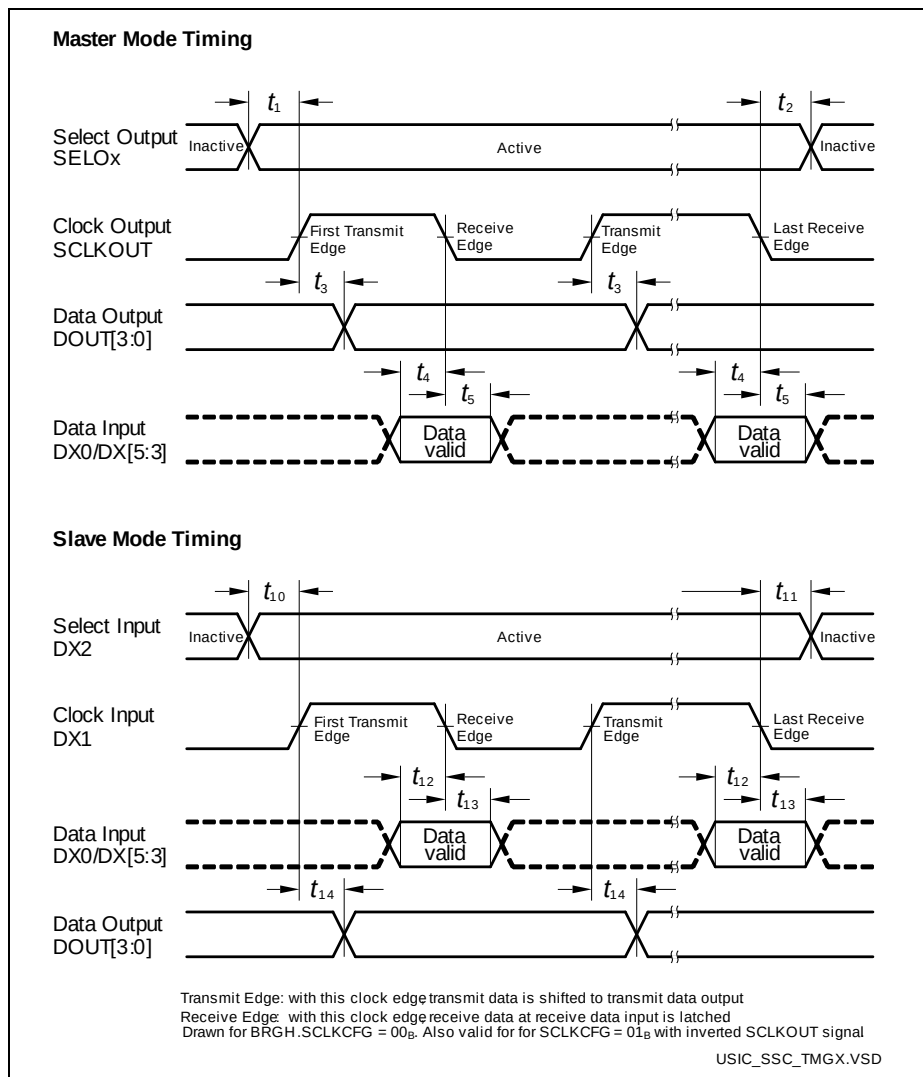


Figure 16 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration, for which the slave select signal is low-active, and the serial clock signal is not shifted and not inverted.

3.3.7.2 Inter-IC (IIC) Interface Timing

The following parameters are applicable for a USIC channel operated in IIC mode.

Note: Operating Conditions apply.

Table 27 USIC IIC Standard Mode Timing¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	-	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	-	-	1000	ns	
Data hold time	t_3 CC/SR	0	-	-	μs	
Data set-up time	t_4 CC/SR	250	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	4.7	-	-	μs	
HIGH period of SCL clock	t_6 CC/SR	4.0	-	-	μs	
Hold time for (repeated) START condition	t_7 CC/SR	4.0	-	-	μs	
Set-up time for repeated START condition	t_8 CC/SR	4.7	-	-	μs	
Set-up time for STOP condition	t_9 CC/SR	4.0	-	-	μs	
Bus free time between a STOP and START condition	t_{10} CC/SR	4.7	-	-	μs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

Table 28 USIC IIC Fast Mode Timing ¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1 * C _b ²⁾	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1 * C _b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	μs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	μs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	μs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	μs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	μs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	μs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	μs	
Capacitive load for each bus line	C _b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

The internal power consumption is defined as

$$P_{\text{INT}} = V_{\text{DDP}} \times I_{\text{DDP}} \text{ (switching current and leakage current).}$$

The static external power consumption caused by the output drivers is defined as

$$P_{\text{IOSTAT}} = \Sigma((V_{\text{DDP}} - V_{\text{OH}}) \times I_{\text{OH}}) + \Sigma(V_{\text{OL}} \times I_{\text{OL}})$$

The dynamic external power consumption caused by the output drivers (P_{IODYN}) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce V_{DDP} , if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

5 Quality Declaration

Table 32 shows the characteristics of the quality parameters in the XMC1300.

Table 32 Quality Parameters

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	V_{HBM} SR	-	2000	V	Conforming to EIA/JESD22-A114-B
ESD susceptibility according to Charged Device Model (CDM) pins	V_{CDM} SR	-	500	V	Conforming to JESD22-C101-C
Moisture sensitivity level	MSL CC	-	3	-	JEDEC J-STD-020C